TOSHIBA Thyristor Silicon Planar Type

S 6 9 9 2

Condenser Discharge Control Applications

- Critical rate of rise of ON-state current: $di/dt = 750 \text{ A/}\mu\text{s}$
- Repetitive surge ON-state current: $ITRM = 500 \text{ A} (t_W = 2 \mu \text{s})$
- Repetitive peak OFF-state voltage: VDRM = 800 V
- Gate trigger current: IGT = 20 mA max.

Maximum Ratings

Characteristics	Symbol	Rating	Unit	
Repetitive peak OFF-state voltage	V_{DRM}	800	V	
Repetitive peak surge ON-state current (Note)	I _{TRM}	500	Α	
Critical rate of rise of ON-state current (Note)	di/dt	750	A/μs	
Peak gate power dissipation	P_{GM}	5	W	
Average gate power dissipation	P _{G (AV)}	0.5	W	
Peak forward gate voltage	V_{FGM}	10	V	
Peak reverse gate voltage	V_{RGM}	-5	V	
Peak forward gate current	I _{GM}	2	Α	
Junction temperature	Tj	-40~125	°C	
Storage temperature range	T _{stg}	-40~150	°C	

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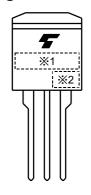
1.4MAX

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Weight: 1.5g (Typ.)

Note: $V_D \le 0.8 \times \text{rated}$, $T_C = 85^{\circ}\text{C}$, $i_{gp} \ge 40$ mA, $t_{gw} \ge 10$ μs , $t_{gr} \le 150$ ns

Marking



※ 1	TYPE NAME	S6992	MARK	S6992
* 2		ng from alphabet A) cimal digit of the	Example 8A: January 1998 8B: February 1998 8L: December 199	

*: There is no reverse-blocking (reverse voltage) ability.

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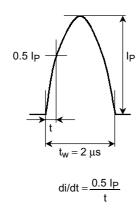
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Electrical Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Repetitive peak OFF-state current	I _{DRM}	V _{DRM} = rated	_	_	10	μΑ
Peak ON-state voltage	V_{TM}	I _{TM} = 25 A	_	_	1.5	V
Gate trigger voltage	V_{GT}	$V_D = 6 \text{ V}, R_I = 10 \Omega$	_	_	1.0	V
Gate trigger current	I _{GT}	VD = 0 V, KL = 10.22	_	_	20	mA
Gate non-trigger voltage	V_{GD}	V _D = rated, Tc = 125°C	0.2	_	_	V
Critical rate of rise of OFF-state voltage	dv/dt	V _{DRM} = rated, Tc = 125°C Exponential rise	_	50	_	V/μs
Holding current	lΗ	V _D = 6 V, I _{TM} = 1 A	_	_	40	mA
Thermal resistance	R _{th (j-a)}	Junction to ambient	_	_	70	°C/W



Test Circuit Examples

